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# HAXPES reference spectra of bulk Mo and MoSe<sub>2</sub> with Cr $K_{\alpha}$ excitation

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Monochromatic Cr  $K_{\alpha}$  radiation (5414.8 eV) was used to acquire high-energy photoelectron spectroscopy (HAXPES) data on pure Mo and bulk MoSe<sub>2</sub> compound with special attention paid to binding energy scale correction and quantification. The reported spectra include a survey scan and high-resolution Mo 2*s*, Mo 2*p*<sub>1/2</sub>, Mo 2*p*<sub>3/2</sub>, Mo 3*d*, Mo 3*p*<sub>1/2</sub>, Mo 3*p*<sub>3/2</sub>, Mo 3*s*, Mo 4*s*, Mo4*p*, Se2*s*, Se 2*p*<sub>1/2</sub>, Se 2*p*<sub>3/2</sub>, Se 3*s*, Se 3*p*<sub>1/2</sub>, Se 3*p*<sub>3/2</sub>, and Se 3*d* core-levels. The data will be useful as reference core-level spectra for HAXPES studies on molybdenum and its compounds.

*Keywords:* Mo, MoSe<sub>2</sub>, HAXPES, Cr  $K_{\alpha}$ 

### INTRODUCTION

Mo and its compounds are widely used in mechanics, electronics and phototonics, as well as in chemistry and catalysis. Recently developed laboratory based hard x-ray photoelectron spectrometers (HAXPES) allow to excite deeper core-levels, enabling different probing depths as a function of the studied core-level. In the case of Mo and MoSe<sub>2</sub>, Cr  $K_{\alpha}$  radiation (5414.8 eV) allows to ionize all Mo and Se core-levels of principal quantum numbers N=2, 3 and 4. In this work, we report HAXPES spectra recorded on pure bulk Mo and MoSe<sub>2</sub> compound. The data include a survey scan and high-resolution spectra of Mo 2*s*, Mo 2*p*<sub>1/2</sub>, Mo 2*p*<sub>3/2</sub>, Mo 3*d*, Mo 3*p*<sub>1/2</sub>, Mo 3*p*<sub>3/2</sub>, Mo 3*s*, Mo 4*s*, Mo4*p*, Se2*s*, Se 2*p*<sub>1/2</sub>, Se 2*p*<sub>3/2</sub>, Se 3*s*, Se 3*p*<sub>1/2</sub>, Se 3*p*<sub>3/2</sub>, and Se 3*d*.

### SPECIMEN DESCRIPTION (ACCESSION # 01900)

Specimen: Mo

CAS Registry #: (Mo) 1317-33-5

**Specimen Characteristics:** Homogeneous; solid; polycrystalline; conductor; metal; Other

Chemical Name: Molybdenum

Composition: Mo

Form: Polycrystalline solid

Structure: Body-centered cubic

**History & Significance:** Air exposed thick Mo and bulk MoSe<sub>2</sub> samples

As Received Condition: Bulk Mo metal

Analyzed Region: Same as specimen

**Ex Situ Preparation/Mounting:** The sample was mounted on the sample holder using double sided conductive tape.

Accession#: 01900, 01901 Technique: XPS Specimen: Mo, MoSe<sub>2</sub> Instrument: ULVAC-PHI Quantes Major Elements in Spectra: Mo, Se Minor Elements in Spectra: O, C Published Spectra: 22 Spectral Category: Reference

**In Situ Preparation:** The Mo sample was sputter cleaned by Ar<sup>+</sup> ions (2 keV) for 5 minutes prior to measurements to remove carbon and oxygen contamination.

**Charge Control:** Low-energy electrons (1 eV, filament 1.1 A) and low-energy  $Ar^+$  ions (100 eV)

Temp. During Analysis: 300 K

Pressure During Analysis: < 2×10<sup>-7</sup> Pa

Pre-analysis Beam Exposure: 0 s

### SPECIMEN DESCRIPTION (ACCESSION # 01901)

Specimen: MoSe<sub>2</sub>

CAS Registry #: (MoSe2) 12058-18-3

Specimen Characteristics: Homogeneous; solid; polycrystalline; semiconductor -

Chemical Name: Molybdenum diselenide

Composition: MoSe<sub>2</sub>

Form: Polycrystalline solid

Structure: Hexagonal

History & Significance: Air exposed bulk MoSe<sub>2</sub> sample

As Received Condition: Bulk MoSe<sub>2</sub>

Analyzed Region: Same as specimen

**Ex Situ Preparation/Mounting:** The sample was mounted on the sample holder using double sided conductive tape.

In Situ Preparation: None

**Charge Control:** Low-energy electrons (1 eV, filament 1.1 A) and low-energy  $Ar^+$  ions (100 eV)

Temp. During Analysis: 300 K

Pressure During Analysis: < 2×10<sup>-7</sup> Pa

Pre-analysis Beam Exposure: 0 s

### **INSTRUMENT DESCRIPTION**

Manufacturer and Model: ULVAC-PHI Quantes

Analyzer Type: spherical sector

Detector: multichannel resistive plate

Number of Detector Elements: 32

# INSTRUMENT PARAMETERS COMMON TO ALL SPECTRA

### ■Spectrometer

Analyzer Mode: constant pass energy

**Throughput (T=E<sup>N</sup>):** The energy dependence can be modeled using the following equation:  $\frac{A}{E_p} = (\frac{a^2}{a^2 + R^2})^b$ , where a and b are constants, E<sub>p</sub> is the pass energy, A is the peak area and R is the retard ratio equal to E/E<sub>p</sub>, where E is the kinetic energy. Three spectral regions are recorded on a sputter cleaned sample at different pass energies. The values of a and b are then determined by a linear least square fit of the data applying the equation described above.

### Excitation Source Window: Al

**Excitation Source:** Cr  $K_{\alpha}$  monochromatic

Source Energy: 5414.8 eV

Source Strength: 50 W

Source Beam Size: 100 µm x 100 µm

Signal Mode: multichannel direct

■Geometry

Incident Angle: 22 °

Source-to-Analyzer Angle: 46 °

Emission Angle: 45 °

Specimen Azimuthal Angle: 0 °

Acceptance Angle from Analyzer Axis: 0 °

Analyzer Angular Acceptance Width:  $20 \degree \times 20 \degree$ 

∎Ion Gun

Manufacturer and Model: ULVAC-PHI Quantes

Energy: 2000 eV

Current: 0.001 mA

Current Measurement Method: Faraday cup

Sputtering Species: Ar

**Spot Size (unrastered):** 100 μm

Raster Size: 3000 µm x 3000 µm

Incident Angle: 45 °

Polar Angle: 45 °

Azimuthal Angle: 45 °

**Comment:** Differentially pumped ion gun used for presputtering of the sample and to prevent reoxidation during analysis.

### DATA ANALYSIS METHOD

Energy Scale Correction: The decrease of photoionization cross-sections in HAXPES (Refs. 1 and 2) leads to a very low intensity of the C 1s core-level peak which is often used to correct the energy scale. Also, in the case of metals, great care must be taken regarding the reliability of energy scale correction relying on the C 1s binding energy of adventitious carbon (Ref. 3). Therefore, the binding energy correction of the data of pure Mo was performed by first considering the binding energy of the Mo  $3d_{5/2}$  peak recorded with Al  $K_{\alpha}$  radiation on the sputter-clean surface referenced to the Fermi level, as determined from a fitting of the band onset. Then, the correction factor was found by aligning on this value the Mo  $3d_{5/2}$  binding energy measured with Cr  $K_{\alpha}$  radiation. Doing so, the Mo  $3d_{5/2}$  binding energy was 227.8 eV, in agreement with an average of 24 binding energy values published in the NIST Database (Ref. 4). The spectra recorded with the Cr  $K_{\alpha}$  source were then rescaled by shifting the Mo  $3d_{5/2}$ to 227.8 eV. Regarding bulk MoSe<sub>2</sub>, the C 1s peak in HAXPES is too weak to be considered for correction of the energy scale. In XPS, the strong Se Auger line completely overlaps the C 1s core line. Therefore, the energy correction of the HAXPES data is made by applying to all spectra an energy shift which is the difference between the Mo  $3d_{5/2}$  binding energy measured by XPS and the Mo  $3d_{5/2}$  binding energy measured by HAXPES. Doing so, the Mo  $3d_{5/2}$  binding energy was 228.9 eV, in good agreement with other data (Ref. 5). The spectra recorded with the Cr  $K_{\alpha}$ source were then rescaled by shifting the Mo  $3d_{5/2}$  to 228.9 eV.

**Recommended Energy Scale Shift:** -0.6 eV for bulk Mo and +0.4 eV for bulk MoSe<sub>2</sub>.

**Peak Shape and Background Method:** Shirley background was employed for peak area determination. No curve fitting was performed on the spectra.

Quantitation Method: PHI Multipak software Version 9.9.0.8 was used to perform quantification. The determined intensities were checked for repeatability by comparing, before and after acquisition, the intensities of the Mo 2s core-line of both samples on the one hand, and on the other hand the intensity of the Ag 3d line of a sputter-clean, bulk silver sample mounted on the same holder. In all cases the standard deviation in intensity was below 6%. Empirically determined sensitivity factors (RSFs) were provided by the software, from the most recently released RSF database. The RSFs were derived from the pure-element relative sensitivity factor as defined in ISO 18118:2015 (Ref 6) which were measured on pure element samples using a Cr  $K_{\alpha}$  source. They therefore account for the decrease of cross-section and different escape depth of photoelectrons using higher energy photons. RSFs are reported proportional to the RSF of F 1s equal to 1. Using the determined pure element RSF's leads to quantification error of ~5% for the MoSe<sub>2</sub> compound.

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### AUTHOR DECLARATION

The authors have no conflict to disclose.

### DATA AVAILABILITY STATEMENT

The data that supports the findings of this study are available within the article and its supplementary material.

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SPECTRAL FEATURES TABLE							
Spectrum	Element/	Peak	Peak	Peak Area	Sensitivity	Concentration	Peak Assignment
ID #	Transition	Energy	Width	(eV x cts/s)	Factor	(at. %)	
		(eV)	FWHM				
			(eV)				
01900-02	Mo 2 <i>p</i> <sub>3/2</sub>	2521.0	2.36	36812	9.584		
01900-03	Mo 2p1/2	2625.8	2.40	20306	4.969		
01900-04	Mo 2s	2866.7	4.17	16358	3.805		
01900-05	Mo 3 <i>d</i>	227.8	1.26	3360	1.103		
01900-06	Mo 3p <sub>3/2</sub>	393.7	2.81	7093	2.063		
01900-06	Mo 3p1/2	411.0	2.60	3222	1.134		
01900-07	Mo 3s	505.3	6.25	3969	0.971		
01900-08	Mo 4s	62.7	4.76	1158	0.284		
01900-09	Mo 4 <i>p</i>	35.4	3.54	1558	0.425		
01901-02	Mo 2 <i>p</i> <sub>3/2</sub>	2521.9	2.37	7307	9.584		
01901-03	Mo 2p <sub>1/2</sub>	2626.9	2.36	3897	4.969		
01901-04	Mo 2s	2867.9	4.47	3459	3.805		
01901-05	Mo 3 <i>d</i> , Se 3 <i>s</i>	229.1	2.34	1610	1.103, 0.708		
01901-06	Mo 3p <sub>3/2</sub>	394.7	2.86	1311	2.063		
01901-06	Mo 3 <i>p</i> 1/2	412.3	2.58	803	1.134		
01901-07	Mo 3s	506.8	4.93	734	0.971		
01901-08	Mo 4s	63.2	3.04	149	0.284		
01901-08	Se 3 <i>d</i>	54.9	1.75	216	1.245		
01901-09	Mo 4 <i>p</i>	36.9	3.49	311	0.425		
01901-10	Se 2p <sub>3/2</sub>	1433.7	1.69	6956	5.135		
01901-11	Se 2p <sub>1/2</sub>	1474.6	1.69	3915	2.773		
01901-12	Se 2s	1653.7	4.85	5183	3.355		
01901-13	Se 3p <sub>3/2</sub>	161.0	2.16	841	0.809		
01901-13	Se 3p <sub>1/2</sub>	166.6	2.24	357	0.436		

ANALYZER CALIBRATION TABLE								
Spectrum ID	Element/	Peak Energy	Peak Width	Peak Area	Sensitivity	Concentration	Peak	
#	Transition	(eV)	FWHM (eV)	(eV x cts/s)	Factor	(at. %)	Assignment	
	Ag 3 <i>d</i> 5/2	368.17	1.00	724121				
	Cu 2p <sub>3/2</sub>	932.61	0.99	65630				
	Au 4 <i>f</i> <sub>7/2</sub>	83.96	0.83	73825				

Comment to Analyzer Calibration Table: The spectra in the analyzer calibration table were recorded using Al  $K_{\alpha}$  photons.

GUIDE TO FIGURES							
Spectrum (Accession) #	Spectral Region	Voltage Shift*	Multiplier	Baseline	Comment #		
01900-01	Survey	0	1	0			
01900-02	Mo 2p <sub>3/2</sub>	+0.6	1	0			
01900-03	Mo 2p <sub>1/2</sub>	+0.6	1	0			
01900-04	Mo 2s	+0.6	1	0			
01900-05	Mo 3 <i>d</i>	+0.6	1	0			
01900-06	Mo 3 <i>p</i>	+0.6	1	0			
01900-07	Mo 3s	+0.6	1	0			
01900-08	Mo 4s	+0.6	1	0			
01900-09	Mo 4p	+0.6	1	0			
01901-01	Survey	0	1	0			
01901-02	Mo 2p <sub>3/2</sub>	-0.4	1	0			
01901-03	Mo 2p <sub>1/2</sub>	-0.4	1	0			
01901-04	Mo 2s	-0.4	1	0			
01901-05	Mo 3 <i>d</i> , Se 3 <i>s</i>	-0.4	1	0			
01901-06	Mo 3p	-0.4	1	0			
01901-07	Mo 3s	-0.4	1	0			
01901-08	Mo 4 <i>s</i> , Se 3 <i>d</i>	-0.4	1	0			
01901-09	Mo 4p	-0.4	1	0			
01901-10	Se 2p <sub>3/2</sub>	-0.4	1	0			
01901-11	Se 2p <sub>1/2</sub>	-0.4	1	0			
01901-12	Se 2s	-0.4	1	0			
01901-13	Se 3p <sub>3/2</sub> , Se 3p <sub>1/2</sub>	-0.4	1	0			





















Accession #	01901-01	
∎ Specimen	MoSe <sub>2</sub>	
■ Technique	XPS	
Spectral Region	Survey	
Instrument	ULVAC-PHI Quantes	
Excitation Source	Cr $K_{\alpha}$ monochromatic	
Source Energy	5414.8 eV	
Source Strength	50 W	
Source Size	0.1 mm x 0.1 mm	
Analyzer Type	spherical sector analyzer	
Incident Angle	22°	
Emission Angle	45°	
Analyzer Pass Energy	280 eV	
Analyzer Resolution	2.33 eV	
Total Signal Accumulation Time	5238 s	
Total Elapsed Time	5760 s	
Number of Scans	10	
Effective Detector Width	31 eV	























